Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO.		
					239462US0		10/601,806		
OIPE					APPLICANT				
LIST OF REFERENCES CITED BY APPLICA					Tsunehiko SÜGAWARA, et al.				
		- 1	OCT 2 0 2003 🕏		FILING DATE		GROUP		
		/	2000	1	June 24, 2003		2879		
U.S. PATENT DOCUMENTS									
EXAMI	NER		DECURENT	DATE	NAME	CLASS SUB FILING DAT		ING DATE	
INITIAL			NUMBER	DATE	INAME	CLASS	CLASS IF APPROPRIATE		PROPRIATE
711		AA	4,253,861	03/03/81	W. A. GRAFF, et al.				
+		AB	3,850,605	11/26/74	W. R. MALTMAN, et al.				
FOREIGN PATENT DOCUMENTS									
			DOCUMENT		COUNTRY		TRANSLATION		
			NUMBER	DATE			YES	ES NO	
M		AC	2001-302278.	10/31/2001	JAPAN				х
1		AD	48-71672 ·	09/27/73	JAPAN				×
	-	AΕ	55-144451 .	11/11/80	JAPAN (with English Abstract)				×
		AF	61-232250	10/16/86	JAPAN (with English Abstract)				х
		AG	57-175751;	10/28/82	JAPAN (with English Abstract)				х
		АН	55-167158 .	12/26/80	JAPAN (with English Abstract)				×
		Al	55-167157 .	12/26/80	JAPAN (with English Abstract)				X
		AJ	54-21366	07/30/79	JAPAN (with corr. US 4,253,861)				х
<u> </u>		AK	46-1329	09/20/71	JAPAN				х
		AL	2939415	08/25/99	JAPAN (with English Abstract)				Х
		АМ	2001-294442	10/23/2001	JAPAN (with English Abstract)				Х
		AN	2001-348245	12/18/2001	JAPAN (with English Abstract)				×
		AO	2001-348248 .	12/18/2001	JAPAN (with English Abstract)	-			×
	1	AP	2002-60242	02/26/2002	JAPAN (with English Abstract)				х
		AQ	2904067 -	06/14/99	JAPAN				×
		AR	53-41691 .	11/06/78	JAPAN (with corr. US 3,850,605)				×
	1	AS	4-285039	10/09/92	JAPAN (with English Abstract)				×
		AT	6-115974	04/26/94	JAPAN (with English Abstract)				×
	1	ΑU	55-154352	12/01/80	JAPAN (with English Abstract)				x
		ΑV	53-3413	01/13/78	JAPAN				x
	1/	AW	54-30688 ·	10/02/79	JAPAN (with English Abstract)				×
(	<b>X</b>	AX	49-23216 .	03/01/74	JAPAN				×
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
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		AY							
		AZ	. ^	<u> </u>		Additional References sheet(s) attached			
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Examiner Date Considered 9/20/09									
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									